

# eGaN® FETs for Photo-Voltaic Inverter Applications



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eGaN® FETs from EPC offer significantly lower capacitance and inductance and zero  $Q_{RR}$  in a smaller device for a given  $R_{DS(on)}$  than comparable MOSFETs. This reduces switching losses resulting in higher efficiency and/or higher switching frequency. Photo-Voltaic (PV) inverter size and cost are dominated by thermal management and passive elements used for bulk energy storage and filtering. Using eGaN FETs to increase efficiency and/or increase switching frequency will reduce the size and cost of the system.

Producible, reliable 600 V GaN devices have been a difficult endeavor by many companies. This makes it difficult to manufacture a large enough die to reduce  $R_{DS(on)}$  to a level where on-state losses are manageable. Today's highest frequency, most efficient PV inverter can be realized by using a four-level architecture using 200 V eGaN FETs, whether in the DC-DC Boost front end converter or DC-AC inverter.

## Four Level Inverter Operation

Figure 1 shows a simplified block diagram for a PV inverter based on a two step conversion approach. The first converter functions as the maximum power point tracker (MPPT) and delivers energy into an intermediate link bus. This bus can be a DC voltage or modulated with a low frequency (twice that of the grid). The inverter is then used to convert the DC voltage or intermediate bus into an Alternating Current that feeds into the grid. A suitable topology is needed to realize this configuration.

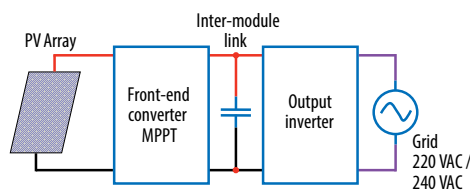


Figure 1: Simplified block diagram for a PV inverter

The basis of the four level inverter allows for operation using lower voltage FETs in that the bus voltage is divided over three capacitors. Instead of 600 V devices, 200 V devices, such as the EPC2010C [1], can be used. The EPC2010C is a 200 V eGaN FET with 25 mΩ maximum  $R_{DS(on)}$ , 5 nC typical  $Q_{Gr}$ , 40 nC  $Q_{OSS}$ , and zero  $Q_{RR}$ . PV Inverters are required to have very high conversion efficiencies that ensure high energy yield over a wide PV array operating range. eGaN FET technology provides both conduction and switching loss advantages over traditional IGBTs and MOSFETs making them ideal candidates for use in a PV Inverter.

Figure 2 shows the four level half bridge topology suitable for use in the PV Inverter. The DC Link capacitors divide the bus voltage by three and each level transistor is clamped to the appropriate divided voltage. For example, a 375 V bus would be divided into 125 V levels, and Q1 would be clamped to the first 125 V level through D1. Assuming current flowing in from the output and Q1, Q2 and Q3 are all on, then Q4, Q5, and

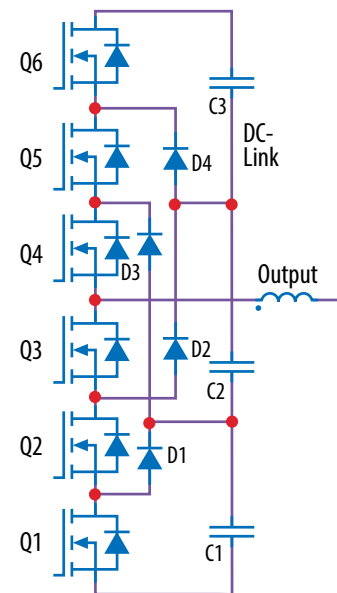


Figure 2: Four level half bridge topology

Q6 would each have 125 V from Drain to Source. The commutation sequence of the switches is shown in figure 3 for both current sink and source directions. This sequence is required to ensure that none of the devices experiences an over-voltage. Timing of the switching sequence can be adjusted to ensure voltage balancing of the bus capacitors since they will each carry the full load current at some time during the switching interval. The timing sequence can be implemented using a simple low cost micro-controller.

The four level topology can then be used as a building block for both the front-end converter, where one would be needed, and the inverter where two would be needed.

## Freewheel Diodes

D1 through D4 in figure 2 are clamp diodes for each level. They only have a short pulse of current during the commutation sequence, but the stored charge is actively recovered during each cycle. Reverse recovery losses will dominate

performance. To reduce the reverse recovery losses for diode commutation, SiC diodes can be used. In the case of D2 and D3, those must furthermore be rated at twice the voltage of each of the bus capacitors as there are switching conditions that exist where twice the voltage can appear momentarily. For diodes D1 and D4, and to further reduce  $Q_{RR}$  losses, the EPC2012C [2] eGaN FET with shorted gate can be substituted.

During the converter body diode conduction periods, shown on figure 3 as the ZVS switching interval, the turn on of the FETs may occur simultaneously at the time the last FET would have been turned on. In the case of the hard-switching event, shown on figure 3, the FETs may be turned off simultaneously only if it is known that there is sufficient load current to ensure that all the devices will conduct using their body diodes.

### Gate Drive

eGaN FETs require 4.5 V to 5 V gate drive referenced to each source [3]. Absolute maximum gate drive voltage is 6 V, so care must be taken to regulate each gate drive voltage source. A basic bootstrap can be used for each of the floating FETs, but since the sources of Q5 and Q6 never go to ground, bootstraps must be cascaded to provide sufficient gate drive voltage as shown in figure 4. The UCC27611 [4] eGaN FET gate driver from Texas Instruments is ideally suited for this application since it has an internal 5 V regulator and separate drive terminals for source and sink. The block diagram for the UCC27611 is shown in figure 5.

The signal to drive each gate has to be shifted above the bus voltage with a high enough  $dv/dt$  capability for the switching speed desired. The Si8610BC [5], from Silicon Labs, is a digital isolator has been shown in the EPC9003C [6] 200 V half bridge development board to be capable under similar conditions.

### Thermal Management

Efficiency for a half bridge providing 2.4 kW is estimated at 98% at 150 kHz. Since the power dissipation is spread over six devices for each half

bridge, thermal management becomes easier. The wafer level package provides excellent thermal paths both into the board and out the top [7]. The best scenario would be to have efficient thermal paths to the ambient through the board along with heat sinking on top.

### Synchronous Boost Converter or DC-AC Inverter

This 200 V eGaN FET based multilevel half bridge can be used in either the synchronous boost or

inverter positions. The commutation timing is identical for both so programming controllers does not take extra effort.

### Summary

Gallium Nitride has the fundamental advantages of lower capacitance, lower inductance, zero  $Q_{RR}$  and smaller size. These advantages can be used today to reduce heat sinking, energy storage, and overall solar inverter size using the EPC2010C in a multilevel topology.

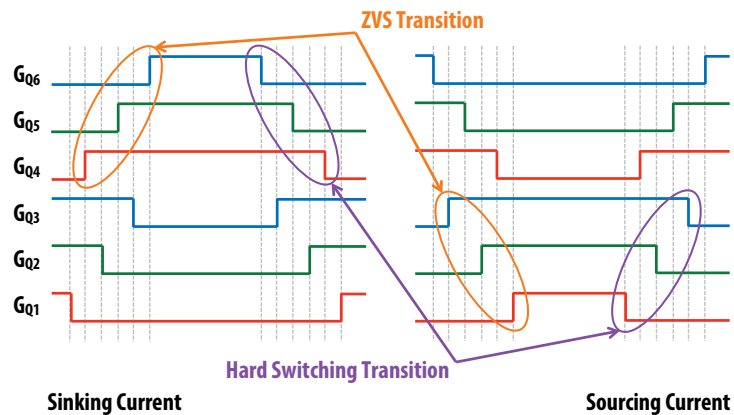


Figure 3: Transistor switching sequencing

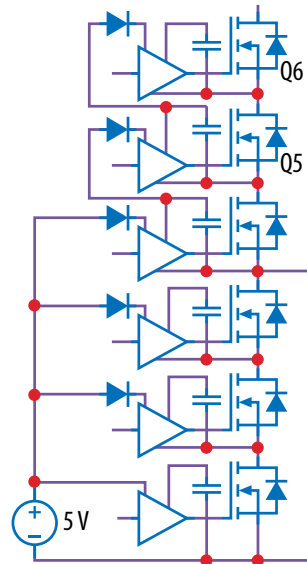


Figure 4: Multilevel eGaN FET gate driver

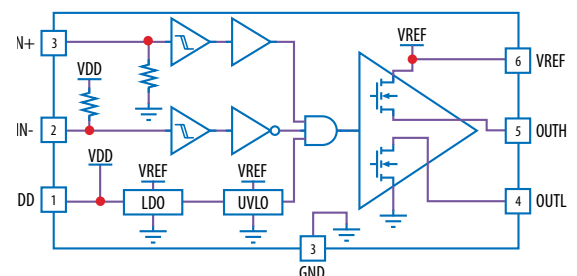


Figure 5: UCC27611 block diagram

### References:

- [1] EPC2010C datasheet, <https://epc-co.com/epc/products/gan-fets-and-ics/epc2010c>
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- [4] UCC27611 datasheet, <https://www.ti.com/lit/ds/symlink/ucc27611.pdf>
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